

Notice of Allowability

Application No.

10/774,014

Examiner

Michael t. Tran

Applicant(s)

HEMINK, GERRIT JAN

Art Unit

2827

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to Amendment filed December 30, 2005.
2. ☒ The allowed claim(s) is/are 1-39 and 52-77.
3. ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) ☐ All b) ☐ Some* c) ☐ None of the:
 1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

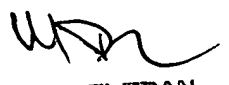
* Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

4. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
5. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
 - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
6. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

1. ☐ Notice of References Cited (PTO-892)
2. ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/08), Paper No./Mail Date _____
4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material
5. ☐ Notice of Informal Patent Application (PTO-152)
6. ☐ Interview Summary (PTO-413), Paper No./Mail Date _____.
7. ☐ Examiner's Amendment/Comment
8. ☒ Examiner's Statement of Reasons for Allowance
9. ☐ Other _____.


MICHAEL TRAN
PPAT, EXAMINER

DETAILED ACTION

1. In response to the Communication dated December 30, 2005, claims 1-39 and 52-77 are active in this application as a result of the cancellation of claims 40-51.

Drawings

2. The drawings filed February 06, 2004 have been approved.

Allowable Subject Matter

3. Claims 1-39 and 52-77 are allowable over the prior art of record.
4. The following is an Examiner's statement of reasons for the indication of allowable subject matter: the prior art of records does not show (in addition to other elements in the claim) the following:
- Boosting through some of the word lines electrical potential(s) of channel regions of the first string of transistors by coupling voltage levels to at least some of the transistors in the first string to reduce program disturb, wherein the electrical potential(s) of the channel regions of some of the transistors in the first string are/is boosted so that breakdown at the drain or source side of the one select transistor in the first string is reduced to such an extent that it does not result in a change of the first transistor's desired charge storage state to a different charge state.

- Boosting through some of the word lines electrical potential(s) of channel regions of the first string of transistors by coupling voltage levels to at least some of the transistors in the first string to reduce program disturb, wherein the electrical potential(s) of the channel regions of some of the transistors in the first string are/is boosted so that such boosting does not result in a change of the first transistor's desired charge storage state to a different one of the more than two possible charge states.
- Boosting electrical potential(s) of channel regions of the first string of transistors by coupling boosting voltage levels to at least some of the transistors and a voltage level to the first transistor in the first string to reduce program disturb, wherein the voltage level coupled to the first transistor is different from that/those coupled to other transistors in the first string when a program voltage level is applied to the control gates coupled to the second and third transistors.
- Coupling first boosting voltage level(s) to all of the transistors in the second string between said selected word line and the bit line connected to the second string to boost electrical potential(s) of channel regions of transistors in the second string to a value or values closer to the program voltage to reduce program disturb.
- Applying second voltage level(s) that are or is less than the first voltage level(s) to word lines controlling the two sets of adjacent transistors to turn off at least one transistor in each set, to reduce program disturb, wherein the second voltage level(s) contain(s) at least one voltage level such that an unprogrammed transistor in the first string coupled to such at least one voltage level will be

turned on but a programmed transistor in the first string coupled to such at least one voltage level(s) will be turned off.

- Coupling second voltage level(s) that are or is less than first voltage level(s) to at least one charge storage transistor in the second string between the selected word line and the source line such that a channel area of the second string on the source side of the at least one transistor coupled to the second voltage is electrically isolated from the transistor in the second string controlled by the selected word line.

5. Any comments considered necessary by applicant must be submitted no later than the payment of the Issue Fee and, to avoid processing delays, should preferably accompany the Issue Fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

6. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Michael T. Tran whose telephone number is (571) 272-1795.

7. Any inquiry of a general nature or relating to the status of this application should be directed to Group receptionist whose telephone number is (571) 272-1650.



Michael T. Tran

February 5, 2006

MICHAEL TRAN
EXAMINER